

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE)
CB SCHEME

CB TEST CERTIFICATE

Product

Multi-port Device Server

Name and address of the applicant

LANTRONIX INC
7535 IRVINE CENTER DR, SUITE 100 IRVINE CA 92618
UNITED STATES

Name and address of the manufacturer

LANTRONIX INC
7535 IRVINE CENTER DR, SUITE 100 IRVINE CA 92618
UNITED STATES

Name and address of the factory

Note: When more than one factory, please report on page 2

HANA MICROELECTRONICS CO LTD (JIA XING)
18 HANA RD XINCHENG INDUSTRIAL PARK XIUZHOU
DISTRICT JIAXING ZHEJIANG 314000
CHINA Additional Information on page 2

Ratings and principal characteristics

100-240Vac; 50/60Hz; 0.25A

Trademark / Brand (if any)



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

EDS3008PR, EDS3016PR, EDS3032PR

Additional information (if necessary may also be reported on page 2)

 Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 60950-1:2005/AMD1:2009, IEC 60950-1:2005/AMD2:2013,
IEC 60950-1:2005

As shown in the Test Report Ref. No. which forms part of this Certificate

E128144-A22-CB-1 issued on 2019-10-18

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2019-10-21

Signature:

Jolanta M. Wroblewska



Ref. Certif. No.

US-34614-UL

Factories:

HANA MICROELECTRONICS PUBLIC CO LTD (LAMPHUN)
NORTHERN REGION INDUSTRIAL ESTATE 101/2 MOO 4 LAMPHUN 51000
THAILAND

PLEXUS MFG SDN BHD

ISLAND VIEW SITE PLOT 40 HILIR SUNGAI KELUANG 4 BAYAN LEPAS FIZ PHASE IV 11900 BAYAN LEPAS
PENANG
MALAYSIA

Additional Information:

Additionally evaluated to EN 60950-1:2006/ A11:2009/ A1:2010/ A12:2011 /A2:2013.
National Differences specified in the CB Test Report.

Additional information (if necessary)



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